

Examiner-Initiated Interview Summary	Application No.	Applicant(s)	
	10/723,982	BINETTE ET AL.	
	Examiner	Art Unit	
	Satyendra K. Singh	1657	

All Participants:

- (1) Satyendra K. Singh.
- (2) Mr. Charlton Shen (attorney of record).

Status of Application: _____

- (3) _____
- (4) _____

Date of Interview: 8 August 2007

Time: 10:30 AM

Type of Interview:

- ☒ Telephonic
- ☐ Video Conference
- ☐ Personal (Copy given to: ☐ Applicant ☐ Applicant's representative)

Exhibit Shown or Demonstrated: ☐ Yes ☒ No

If Yes, provide a brief description:

Part I.

Rejection(s) discussed:
N/A

Claims discussed:
4,6, 14-16


Prior art documents discussed:
N/A

Part II.

SUBSTANCE OF INTERVIEW DESCRIBING THE GENERAL NATURE OF WHAT WAS DISCUSSED:
See Continuation Sheet

Part III.

- ☒ It is not necessary for applicant to provide a separate record of the substance of the interview, since the interview directly resulted in the allowance of the application. The examiner will provide a written summary of the substance of the interview in the Notice of Allowability.
- ☐ It is not necessary for applicant to provide a separate record of the substance of the interview, since the interview did not result in resolution of all issues. A brief summary by the examiner appears in Part II above.


(Examiner/SPE Signature)

(Applicant/Applicant's Representative Signature – if appropriate)

Continuation of Substance of Interview including description of the general nature of what was discussed: Applicant's attorney of record Mr. Charlton Shen (phone 617-439-2782) was contacted by the Examiner (telephonically, after the patentability conference with the Primary examiner Irene Marx and SPE Jon Weber) and was provided (by a fascimile) with a proposed Examiner's Amendment of the pending claims (especially claims 4, 6, 14, 16 and 19-21). Applicant's attorney discussed the issues with claims (in particular amended claims 4, 14 and 16, and cancelling claim 15), and agreed with the proposed Examiner's amendedment to the claims, as approved by the Patentability conference..